

3. A method of determining crystal orientation comprising the steps of

- (a) mounting the crystal in a holder;
- (b) taking a Laue photograph of the crystal;
- (c) determining from the photograph the angular orientation of a plurality of planes of the crystal; 5
- (d) transferring the crystal holder to a diffractometer;
- (e) selecting a first crystal plane for examination by orienting said plane parallel to the axis of the diffractometer; 10
- (f) scanning the crystal with X-rays and monitoring the diffracted X-rays until the Bragg angle corresponding to the selected plane is determined;
- (g) determining the interplanar spacing corresponding to the measured Bragg angle; 15
- (h) determining the Miller indices corresponding to the interplanar spacing so determined;
- (i) repeating steps (e) to (h) for the remaining planes.

4. A method for determining crystal orientation comprising the steps of

- (a) mounting the crystal in a holder; 20
- (b) taking a Laue photograph of the crystal;
- (c) determining from the photograph the relative orientation of a plurality of planes in the crystal;
- (d) transferring the crystal holder to a diffractometer 25

having a source of essentially monochromatic radiation for incident X-rays and a detector for diffracted X-rays;

- (e) selecting a first crystal plane for examination by orienting the normal to said plane in the plane of the incident and diffracted X-rays;
- (f) irradiating the crystal and determining the Bragg angle corresponding to the selected plane; and
- (g) determining the interplanar spacing corresponding to the measured Bragg angle and the wave length of X-radiation used;
- (h) determining the Miller indices of the selected plane for the interplanar spacing so determined;
- (i) repeating steps (e) through (h) for the remaining planes.

#### References Cited

##### UNITED STATES PATENTS

2,432,913 12/1947 Luley ----- 250—51.5

##### OTHER REFERENCES

"The Encyclopedia of X-Rays and Gamma Rays," edited by G. L. Clark, Reinhold Publishing Corp., New York, 1963, pages 676-679.

WILLIAM F. LINDQUIST, Primary Examiner